

## 4: Information and Statistical Inference-1 ①

The story so far ...

\* Information = Reduction in uncertainty

\* Uncertainty  $\approx$  Randomness  $\approx$  Entropy

\* When an unknown  $X$  is revealed, information revealed equals

$$\text{Uncertainty before} - \text{Uncertainty after} = H(X) - 0 = H(X)$$

And now for something completely different ...

How much information is revealed about  $X$  when  $Y$  is revealed?

[A] Statistical Inference: Hypothesis testing and estimation

Let  $(X, Y)$  be jointly distributed with joint distribution  $P_{XY}$ .

Suppose that  $X$  is an unknown and  $Y$  is the observed r.v.

The conditional distribution  $P_{Y|X}(\cdot|x)$  is called

a channel in information theory. We will denote it

by  $W: \mathcal{X} \rightarrow \mathcal{Y}$  and abbreviate  $W_x = P_{Y|X}(\cdot|x)$ .

(For discrete  $\mathcal{X}, \mathcal{Y}$ ,  $W(y|x)$  denotes the prob.  $P(Y=y|X=x)$ .)

→ We can now use  $(W_x, x \in \mathcal{X})$  to represent an experiment

where  $x$  is unknown and  $Y \sim W_x$  are observed. The

goal is to determine  $x$  by observing  $Y \sim W_x$ .

This is the classic Statistical Inference problem.

In our setting, we assume that  $X$  is generated from a fixed distribution  $P_x$ . Such a formulation is called a Bayesian Formulation.

\* Binary Hypothesis Testing:  $|X|=2$

$H_0: Y \sim W_0$     Upon observing  $Y \sim W_x$ , we form an estimate  
 $H_1: Y \sim W_1$      $\hat{X} = g(Y)$ . Our goal is to minimize the average probability of error

$$P(X \neq \hat{X}) = P_x(0) P(g(Y)=1|0) + P_x(1) P(g(Y)=0|1)$$
$$= P_x(0) \sum_{y \in A_0^c} W_0(y) + P_x(1) \sum_{y \in A_0} W_1(y)$$

where  $A_0 = \{y: g(y)=0\}$ .

The distribution  $P_x$  is called the prior.

The distribution  $P_{x|y}(\cdot|y)$  is called the posterior, which can be computed using the Bayes rule:  $P_{x|y}(x|y) = \frac{P_x(x)W(y|x)}{P_y(y)}$

The induced output distribution  $P_y$  is given by

$$P_y(y) = \sum_x P_x(x) W(y|x) =: W_0 P_x(y) \text{ or } W_1 P_x(y).$$

For a uniform prior, i.e.,  $P_x(0) = P_x(1) = \frac{1}{2}$ ,

$$P(\hat{X} \neq X) = \frac{1}{2} W_0(A_0^c) + \frac{1}{2} W_1(A_0)$$
$$= \frac{1}{2} - \frac{1}{2} (W_0(A_0) - W_1(A_0))$$

(3)

Note that we can choose any  $A_0$ . The least probability of error  $P_e^*(\text{unif})$  is given by

$$P_e^*(\text{unif}) = \frac{1}{2} - \frac{1}{2} \max_A (W_0(A) - W_1(A))$$

$$= \frac{1}{2} \cdot (1 - d(W_0, W_1))$$

and is attained by

$$A^* = \{y: W_0(y) \geq W_1(y)\}.$$

The function  $g$  is called a test and the function  $g^*(y) = \mathbb{1}_{\{W_0(y) < W_1(y)\}}$  is called a Bayes optimal test or simply Bayes.

\* M-ary hypothesis testing:  $|\mathcal{X}| = M$

Test  $g: \mathcal{Y} \rightarrow \mathcal{X}$  outputs  $\hat{X} = g(Y)$ .

$$P_e(g|P_x) = P(\hat{X} \neq X)$$

Optimal prob. of error  $\equiv P_e^*(P_x) = \min_{g: \mathcal{Y} \rightarrow \mathcal{X}} P_e(g|P_x)$ .

\* Estimation problem:  $\mathcal{X}$  need not be discrete.

Note that  $P(\hat{X} \neq X) = \mathbb{E}_{P_{X,Y}} [\mathbb{1}_{\{\hat{X} \neq X\}}]$ .

For a general  $\mathcal{X}$ , we can consider an arbitrary loss function  $l: \mathcal{X} \times \mathcal{X} \rightarrow \mathbb{R}_+$ . Then,  $L(g|P_x) := \mathbb{E}_{P_{X,Y}} [l(g(Y), X)]$ .

and optimal loss  $L^*(P_X) = \min_{g: \mathcal{Y} \rightarrow \mathcal{X}} L(g|P_X)$ . (4)

When  $\mathcal{X} = \mathbb{R}^d$ ,  $l(x, x') = \|x - x'\|_2^2 = \sum_{i=1}^d (x_i - x'_i)^2$

is a popular loss function, and  $L(g|P_X)$  is called the Mean Squared Loss (MSE). The quantity  $L^*(P_X)$  in this case is called the Minimum Mean Squared Error (MMSE).

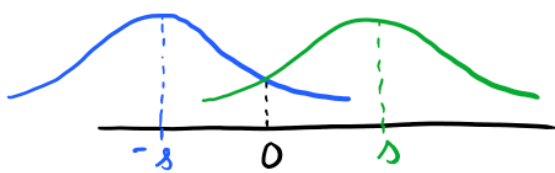
### B) Examples

\* Example 1 (Binary hypothesis testing)

$\mathcal{X} = \{-s, s\}$ ,  $\mathcal{Y} = \mathbb{R}$ ,  $\mathcal{H}_0: Y \sim N(-s, \sigma^2)$ ,  $\mathcal{H}_1: Y \sim N(s, \sigma^2)$

Then,  $P_e^*(\text{unif}) = \frac{1}{2} (1 - d(W_{-s}, W_s))$

where  $d(W_{-s}, W_s) = W_{-s}(\{y: W_{-s}(y) > W_s(y)\}) - W_s(\{y: W_{-s}(y) \leq W_s(y)\})$



$$W_{-s}(A^*) = \mathbb{P}(-s + Z < 0) \quad \text{where } Z \sim N(0, \sigma^2)$$

$$= 1 - \mathbb{P}(Z \geq s)$$

$$= 1 - Q\left(\frac{s}{\sigma}\right) \quad \text{where } Q(t) = \frac{1}{\sqrt{2\pi}} \int_t^{\infty} e^{-t^2/2} dt.$$

$$W_s(A^*) = \mathbb{P}(s + Z < 0) = \mathbb{P}(Z < -s) = Q\left(\frac{s}{\sigma}\right) \quad (\text{why?})$$

(5)

Therefore,  $d(w_{-s}, w_s) = 1 - 2Q\left(\frac{s}{\sigma}\right)$ , and so

$$P_e^*(\text{unif}) = Q\left(\frac{s}{\sigma}\right) \approx e^{-\frac{s^2}{2\sigma^2}}$$

\* Example 2  $\mathcal{X} = \mathcal{Y} = \mathbb{R}^d$ ,  $W_x = N(x, \sigma^2 I)$

Then, for  $g(y) = y$ , we have

↳ Gaussian with mean  $x$ , covariance  $\sigma^2 I$

$L(g|P_x) = d\sigma^2$  for any  $P_x$  (show this)

for the MSE  $L(g|P_x)$ .

\* Example 3 (Testing the bias of a coin)

How many coin tosses are needed to test if a coin is head heavy or tail heavy?

In our framework,  $\mathcal{X} = \left\{\frac{1}{2} - \varepsilon, \frac{1}{2} + \varepsilon\right\}$  and

$\mathcal{Y} = \{0, 1\}^n$ .

$\mathcal{H}_0: Y_1, \dots, Y_n \sim \text{iid Ber}\left(\frac{1}{2} - \varepsilon\right) = P$

$\mathcal{H}_1: Y_1, \dots, Y_n \sim \text{iid Ber}\left(\frac{1}{2} + \varepsilon\right) = Q$

Let  $P^n = P \times \dots \times P$  and  $Q^n = Q \times \dots \times Q$  denote the  $n$ -fold product distributions on  $Y_1, \dots, Y_n$ .

Then, by our formula for  $P_e^*(\text{unif})$ ,

$$P_e^*(\text{unif}) = \frac{1}{2} (1 - d(P^n, Q^n))$$

Suppose we will be happy with  $P_e^*(\text{unif}) \leq \frac{1}{2000}$ . Then,

⑥

we must have  $d(P^n, Q^n) \geq \frac{999}{1000}$ .

Heuristically,  $d(P^n, Q^n)$  grows with  $n$  towards 1. The least number of coin flips we need is the least  $n$  required for  $d(P^n, Q^n)$  to cross  $999/1000$ .

To find an estimate for this least  $n$ , we will derive an upper bound for  $d(P^n, Q^n)$ .

Lemma (Subadditivity of total variation distance)

For  $P^n = P_1 \times P_2 \times \dots \times P_n$  and  $Q^n = Q_1 \times Q_2 \times \dots \times Q_n$ , we have

$$d(P^n, Q^n) \leq \sum_{i=1}^n d(P_i, Q_i).$$

Proof. It suffices to show the claim for  $n=2$  (why?).

$$\begin{aligned} d(P_1 \times P_2, Q_1 \times Q_2) &= \frac{1}{2} \sum_{y_1, y_2} |P_1(y_1)P_2(y_2) - Q_1(y_1)Q_2(y_2)| \\ &= \frac{1}{2} \sum_{y_1, y_2} |P_1(y_1)P_2(y_2) - P_1(y_1)Q_2(y_2) \\ &\quad + P_1(y_1)Q_2(y_2) - Q_1(y_1)Q_2(y_2)| \\ &\leq \frac{1}{2} \sum_{y_1, y_2} |P_1(y_1)P_2(y_2) - P_1(y_1)Q_2(y_2)| \\ &\quad + \frac{1}{2} \sum_{y_1, y_2} |P_1(y_1)Q_2(y_2) - Q_1(y_1)Q_2(y_2)| \\ &\quad \rightarrow \frac{1}{2} \sum_{y_1} P_1(y_1) \sum_{y_2} |P_2(y_2) - Q_2(y_2)| = d(P_2, Q_2) \\ &= d(P_2, Q_2) + d(P_1, Q_1). \end{aligned}$$

Thus, for  $P_{\epsilon^*}(\text{unif}) \leq \frac{1}{2000}$ , we need  $n \geq \frac{999}{1000} \cdot \frac{1}{d(P, Q)}$  (7)

For the coin-toss example,  $d(P, Q) = \epsilon$ . Then, the previous bound suggests that we need  $\geq 1/\epsilon$  coin tosses to distinguish the two coins. In fact, we will see later that this bound is weak and we need many more coin tosses, roughly  $1/\epsilon^2$ . We will see that  $d(P^n, Q^n) \leq \sqrt{n}$  and not just  $\leq n$  as suggested by the lemma above.

### [C] Neyman-Pearson formulation and threshold tests

The Bayes optimal test we saw had the form

$$g(y) = \begin{cases} 0, & \frac{W_0(y)}{W_1(y)} > 1 \\ 1, & \frac{W_0(y)}{W_1(y)} \leq 1 \end{cases}$$
$$= \begin{cases} 0, & \log \frac{W_0(y)}{W_1(y)} > 0 \\ 1, & \log \frac{W_0(y)}{W_1(y)} \leq 0 \end{cases}$$

This suggests the following class of tests:

$$g_{\tau}(y) = \begin{cases} 0, & \log \frac{W_0(y)}{W_1(y)} > \tau \\ 1, & \log \frac{W_0(y)}{W_1(y)} \leq \tau \end{cases}$$



How well do these tests perform?

(8)

$$P_e(g_Z | P_X) = P_{X(0)} \sum_{y: g_Z(y)=1} W_0(y) + P_{X(1)} \sum_{y: g_Z(y)=0} W_1(y)$$

Abbreviating  $P_{X(1)} = p$ ,

$$P_e(g_Z | P) = (1-p) \underbrace{W_0(\{g_Z(y)=1\})}_{\text{Error given } X=0} + p \underbrace{W_1(\{g_Z(y)=0\})}_{\text{Error given } X=1}$$

type I error type II error

As  $\tau$  increases, type-I error increases and type-II error decreases.

Neyman-Pearson considered a slightly different formulation than the average error criterion above.

We seek tests for which error of type-I is less than  $\epsilon$ . Under this constraint, we want to find a test that minimizes the error of type-II. Namely, find a test that attains

$$\beta_\epsilon(W_0, W_1) = \min \left\{ \sum_{y: g(y)=0} W_1(y) : \text{test } g \text{ satisfies} \right. \\ \left. \sum_{y: g(y)=1} W_0(y) \leq \epsilon \right\}$$

→ This is motivated by applications where  $\mathcal{H}_0$  is the normal operation and  $\mathcal{H}_1$  is an alarming situation. Here, the error of type-I is a false alarm and is a less severe error, while



the error of type-II is a missed detection and ⑨  
 is a more severe error. The Neyman-Pearson formulation  
 seeks to minimize the missed detection probability given  
 that the prob. of false alarm is less than  $\varepsilon$ .

→ We evaluate our threshold test  $g_\tau$  for this setting.

$$\begin{aligned} & \text{Prob. of false alarm} \\ &= \text{Prob. of error of type-I} = W_0(\{y: g_\tau(y)=1\}) \\ &= W_0(\{y: \log \frac{W_0(y)}{W_1(y)} \leq \tau\}) \end{aligned}$$

$$\begin{aligned} \text{Prob. of missed detection} &= W_1(\{y: g_\tau(y)=0\}) \\ &= \sum_{y: \log \frac{W_0(y)}{W_1(y)} > \tau} W_1(y) \quad \rightsquigarrow = \frac{W_1(y)}{W_0(y)} \cdot W_0(y) \\ &= \left( 2^{-\log \frac{W_0(y)}{W_1(y)}} \right) \cdot W_0(y) \end{aligned}$$

$$\begin{aligned} &< \sum_y 2^{-\tau} W_0(y) \\ &= 2^{-\tau} \end{aligned}$$

We have shown the following result:

Lemma Suppose that  $\lambda > 0$  satisfies

$$W_0\left(\left\{y: \log \frac{W_0(y)}{W_1(y)} \geq \tau\right\}\right) \geq 1 - \varepsilon.$$

Then,

$$\beta_\varepsilon(W_0, W_1) \leq 2^{-\tau}.$$

For iid observation  $y \equiv y^n$

(10)

$$W_0(y^n) = \prod_{i=1}^n p(y_i), \quad W_1(y^n) = \prod_{i=1}^n q(y_i)$$

Then, by Chebyshev's inequality,

$$P\left(\sum_{i=1}^n \log \frac{p(y_i)}{q(y_i)} \leq n \mathbb{E}_p \left[ \log \frac{p(y_i)}{q(y_i)} \right] + \sqrt{\frac{n}{\varepsilon} \text{Var} \left( \log \frac{p(y_i)}{q(y_i)} \right)}\right) \geq 1 - \varepsilon.$$

### D KL Divergence and Stein's lemma

The quantity  $\mathbb{E}_p \left[ \log \frac{p(y)}{q(y)} \right]$  is called the Kullback-Leibler Divergence and is denoted by  $D(P \parallel Q)$ .

$D(P \parallel Q) = \sum_y p(y) \log \frac{p(y)}{q(y)}$  is the counterpart of

$d(P, Q)$  that enters the Neyman-Pearson formulation.

Our lemma in part C shows:

$$\lim_{n \rightarrow \infty} -\frac{1}{n} \log \beta_\varepsilon(P^n, Q^n) \geq D(P \parallel Q)$$

Stein's lemma

$$\lim_{n \rightarrow \infty} -\frac{1}{n} \log \beta_\varepsilon(P^n, Q^n) = D(P \parallel Q),$$

Namely, the largest exponential decay rate of  $\beta_\varepsilon(P^n, Q^n)$  is  $D(P \parallel Q)$  and is attained by threshold tests.

(11)

$D(P||Q)$  has a similar interpretation as  $d(P, Q)$ : if  $D(P||Q)$  is small, the hypotheses  $P$  and  $Q$  are difficult to distinguish. Stein's lemma gives an asymptotic justification of this fact. Later we will see another justification that holds for a fixed  $n$ .

Example  $P \equiv \text{Ber}(\frac{1}{2})$ ,  $Q \equiv \text{Ber}(\frac{1+\varepsilon}{2})$

$$d(P, Q) = \frac{\varepsilon}{2}$$

$$D(P||Q) = \frac{1}{2} \log \frac{1}{1+\varepsilon} + \frac{1}{2} \log \frac{1}{1-\varepsilon} = \frac{1}{2} \log \frac{1}{1-\varepsilon^2}$$

$$= \frac{1}{2 \ln 2} \ln \frac{1}{1-\varepsilon^2} \geq \frac{\varepsilon^2}{2 \ln 2} = \frac{2}{\ln 2} d(P, Q)^2$$

(why?)

\* Continuous distributions

For  $P$  and  $Q$  with densities  $f$  and  $g$ ,

$$D(P||Q) := \int f(x) \log \frac{f(x)}{g(x)} dx.$$

This definition serves exactly the same purpose as that for the discrete case (In fact, both can be recovered as special cases of a more general definition)

The log-likelihood ratio tests  $\mathcal{J}_\tau$  can now be replaced with  $\sum_{i=1}^n \log f(x_i)/g(x_i) \stackrel{0}{\geq} \tau$ , with the same performance.

## [E] Properties of KL divergence (proofs will be given later)

(12)

### (1) Data processing inequality

"Distances b/w distributions decreases when you further process their samples"

- Agrees with our heuristic that these distances determine how difficult is it to test between the two distributions.

(since we can apply tests to the processed samples)

Let  $P$  and  $Q$  be two distributions on  $\mathcal{Y}$ , and let

$W: \mathcal{Y} \rightarrow \mathcal{Z}$  be a fixed channel (representing the data processing operation).

Then,

$$(i) \quad d(W \circ P, W \circ Q) \leq d(P, Q)$$

$$(ii) \quad D(W \circ P, W \circ Q) \leq D(P \parallel Q)$$

### (2) Pinsker's inequality

(The bound of our example is tight)

$$D(P \parallel Q) \geq \frac{2}{\ln 2} d(P, Q)^2$$

This bound says that  $D(P \parallel Q)$  behaves roughly the same as

the square of distance (what is special about squared distance in Euclidean space?)

### (3) Additivity

$$D(P_1 \times \dots \times P_n \parallel Q_1 \times \dots \times Q_n) = \sum_{i=1}^n D(P_i \parallel Q_i)$$